

# TK4A50D

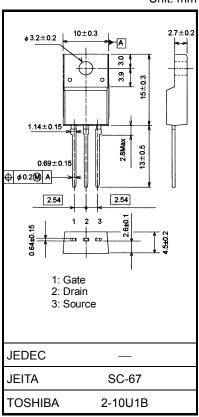
### **Switching Regulator Applications**

Unit: mm

- Low drain-source ON-resistance:  $RDS(ON) = 1.7 \Omega(typ.)$
- High forward transfer admittance:  $|Y_{fs}| = 1.5 \text{ S (typ.)}$
- Low leakage current:  $IDSS = 10 \mu A (max) (VDS = 500 V)$
- Enhancement mode:  $V_{th} = 2.4 \text{ to } 4.4 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	500	V	
Gate-source voltage		$V_{GSS}$	±30	V	
Drain current	DC (Note 1)	ΙD	4	А	
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	16		
Drain power dissipation (Tc = 25°C)		P <sub>D</sub>	30	W	
Single pulse avalanche energy (Note 2)		E <sub>AS</sub>	156	mJ	
Avalanche current		I <sub>AR</sub>	4	Α	
Repetitive avalanche energy (Note 3)		E <sub>AR</sub>	3.0	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55 to 150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

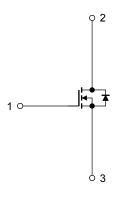
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	4.17	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1:Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD} = 90 \text{ V}$ ,  $T_{ch} = 25^{\circ}\text{C}$  (initial), L = 17 mH,  $R_G = 25 \Omega$ ,  $I_{AR} = 4 \text{ A}$ 

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



## **Electrical Characteristics (Ta = 25°C)**

Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	_	_	±1	μА
Drain cut-off curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V	_	_	10	μА
Drain-source brea	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	500	_	_	V
Gate threshold vo	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.4	_	4.4	V
Drain-source ON	resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2 A	_	1.7	2.0	Ω
Forward transfer	admittance	Yfs	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 2 A	0.4	1.5	_	S
Input capacitance		C <sub>iss</sub>		_	380	_	
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	_	2.5	_	pF
Output capacitance		Coss			45		
Switching time	Rise time	t <sub>r</sub>	10 V V <sub>GS</sub>	_	15	_	
	Turn-on time	t <sub>on</sub>	$\begin{array}{c c} \hline  & & \\ \hline  $	_	35		20
	Fall time	t <sub>f</sub>		_	7		ns
	Turn-off time	t <sub>off</sub>	Duty $\leq$ 1%, $t_W = 10 \mu s$	_	55		
Total gate charge		Qg		_	9		
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 4 \text{ A}$	_	5	_	nC
Gate-drain charge		Q <sub>gd</sub>			4		

# **Source-Drain Ratings and Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	4	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	16	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 4 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 4 A, V <sub>GS</sub> = 0 V,	_	800	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/μs	_	4.4	_	μС

# Marking

